

2019. 4. 2.

①

- Reciprocal vector 2차원의, Bragg's condition & Laue condition.
- Translation 0122 ③
- BCC.

- ↳
- FCC
 - XRD refinement. - prefer orientation
microstrain
 - size
background fn.
 - R.
refine peak 331

2차원 \rightarrow 4. 9.

마감

(XRD, TGA., 친구가 토
bond 층구조 \rightarrow 미너리 - 흡)

2차원 \rightarrow 4. 16

마감

Steel restraint., phase
diagram.

2차원 \rightarrow 4. 23

마감

시험

XRD 2차원
분석.

Glass

Translation of \vec{G} a set of reciprocal lattice vectors

0122 Note ③

Fourier Analysis of the Basis

- Scattering amplitude., $F_{\vec{G}}$ for N cells.

$$F_{\vec{G}} = N \int_{\text{cell}} dV n(\vec{r}) \exp(-i \vec{G} \cdot \vec{r}) = N S_{\vec{G}}$$

(=)

electron concentration.

Structure factor.

Note: Previously Intensity $\propto \left| \int_{\vec{r}} n(\vec{r}) e^{i(\vec{k}-\vec{R}) \cdot \vec{r}} \right|^2$.

$$S_{\vec{G}} = \int_{\text{cell}} dV n(\vec{r}) \exp(-i \vec{G} \cdot \vec{r}) \rightarrow \text{for one cell.}$$

④

$$= \sum_j \int dV n_j(\vec{r} - \vec{r}_j) \exp(-i \vec{G} \cdot \vec{r}) \rightarrow \text{for all basis } j \text{ in one cell}$$

$$= \sum_j \exp(-i \vec{G} \cdot \vec{r}_j) \int dV n_j(\vec{r}) \exp(-i \vec{G} \cdot \vec{r}) \quad \text{where } \vec{\rho} = \vec{r} - \vec{r}_j$$

f_j = atomic form factor. (2차원 분석)

원자 종류

(2)

$$\Rightarrow S_G = \sum_j f_j \exp(-i\vec{G} \cdot \vec{r}_j)$$

if $\vec{r}_j = x_j \mathbf{a}_1 + y_j \mathbf{a}_2 + z_j \mathbf{a}_3$

$$\vec{G} = v_1 \mathbf{b}_1 + v_2 \mathbf{b}_2 + v_3 \mathbf{b}_3, \text{ then}$$

$$\begin{aligned}\vec{G} \cdot \vec{r}_j &= (v_1 \mathbf{b}_1 + v_2 \mathbf{b}_2 + v_3 \mathbf{b}_3) \cdot (x_j \mathbf{a}_1 + y_j \mathbf{a}_2 + z_j \mathbf{a}_3) \\ &= 2\pi (v_1 x_j + v_2 y_j + v_3 z_j) \quad (\mathbf{a}_i \cdot \mathbf{b}_j = 2\pi \delta_{ij})\end{aligned}$$

Also,

$$S_G = \sum_j f_j \exp[-i2\pi(v_1 x_j + v_2 y_j + v_3 z_j)]$$

Example BCC

$$\text{BCC} = SC + 2 \text{ basis} \quad \begin{cases} x_1 = y_1 = z_1 = 0 & \text{atom #1} \\ x_2 = y_2 = z_2 = \frac{1}{2} & \text{atom #2} \end{cases}$$

$$\begin{aligned}S_G &= f_1 \exp[-i2\pi(0)] \\ &\quad + f_2 \exp[-i2\pi(\frac{1}{2}v_1 + \frac{1}{2}v_2 + \frac{1}{2}v_3)]\end{aligned}$$

$$(\text{if } f_1 = f_2 = f_1) = f [1 + \exp[-i\pi(v_1 + v_2 + v_3)]]$$

$$\Rightarrow S_G = 0, \quad \text{when } v_1 + v_2 + v_3 = \text{odd}$$

$$S_G = 2f, \quad \text{when } " = \text{even}$$

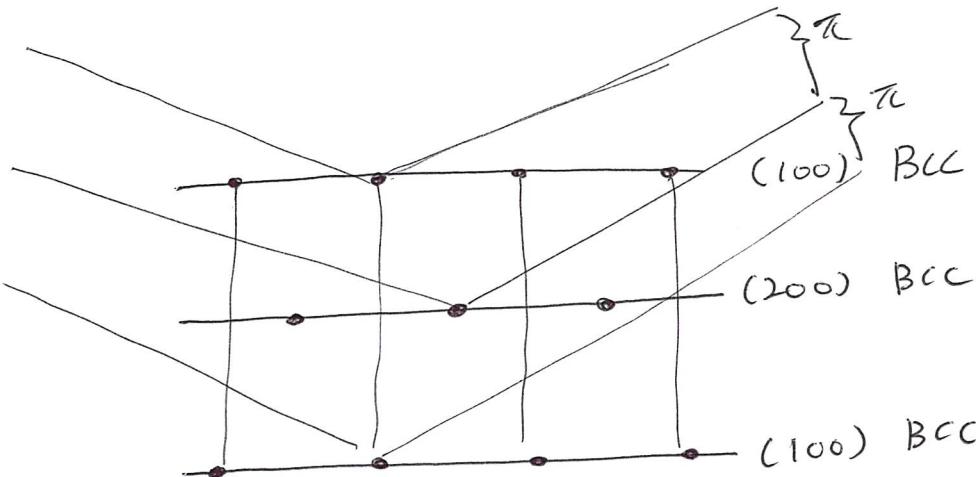
cf.) $e^{-ix} = \cos x - i \sin x.$ ~~if~~

$$x = \text{even}, \quad e^{-i\pi x} = \frac{1}{1 - i\pi x}$$

(3)

$(100), (300), (111) \text{ or } (221) \rightarrow \text{No peaks}$
 $(200), (110), (222) \rightarrow \text{peaks present}$

Note: (V_1, V_2, V_3) indices are referred to a cubic cell.
conventional lattice
 (h, k, l)
(= primitive SC)



$$K = \frac{2\pi}{\lambda} ; (100) \frac{3}{2}\pi \text{ is } 2\pi \rightarrow \text{constructive interference} \quad \text{보강간섭}$$

$$(100), (200) \pi \rightarrow \text{destructive} \quad " \quad \text{상쇄간섭}$$

~~Example~~ ~~KL~~,

(4)

Example FCC.

SSP KCl, KBr 예제 22.

$$FCC = SC + 4 \text{ basis}$$

$$\left\{ \begin{array}{l} (x_j, y_j, z_j) \\ (0, 0, 0) \\ (0, \frac{1}{2}, \frac{1}{2}) \\ (\frac{1}{2}, 0, \frac{1}{2}) \\ (\frac{1}{2}, \frac{1}{2}, 0) \end{array} \right.$$

$$S_G = f [1 + \exp[-i\pi(v_2 + v_3)] + \exp[-i\pi(v_1 + v_3)] \\ + \exp[-i\pi(v_1 + v_2)]]$$

$$\text{All even} \rightarrow S_G = 4f$$

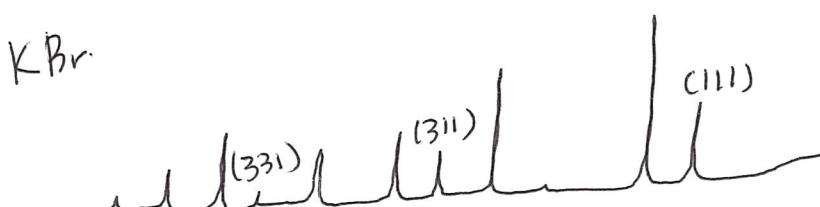
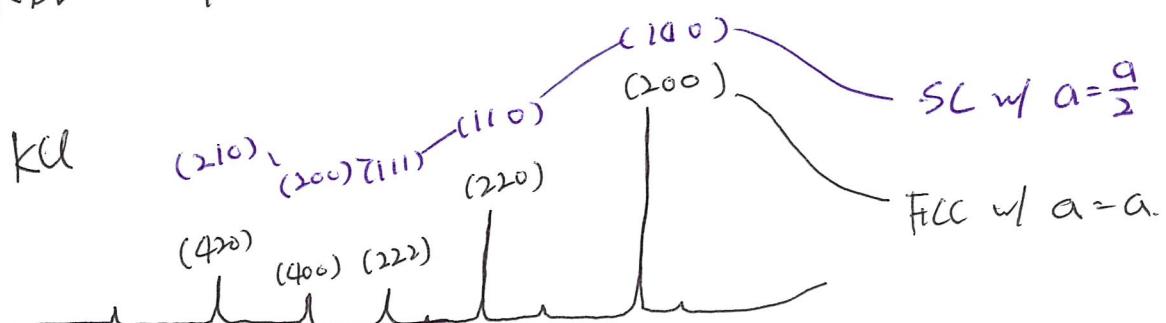
$$\text{All odd} \rightarrow "$$

$$\text{one even} \rightarrow 0$$

$$\text{one odd} \rightarrow 0$$

$$\begin{array}{ll} Br & 35\text{Hz } 32-35\text{MHz} \\ K & 19\text{Hz } 22-19\text{MHz} \\ Cl & 17\text{Hz } 32-17\text{MHz} \end{array}$$

e.g.) KCl $\Rightarrow K^+ + Cl^-$ (long bond), FCC, $f(K^+) \approx f(Cl^-)$
 KBr $\Rightarrow K^+ + Br^-$ (" ", "), $f(K^+) \neq f(Br^-)$

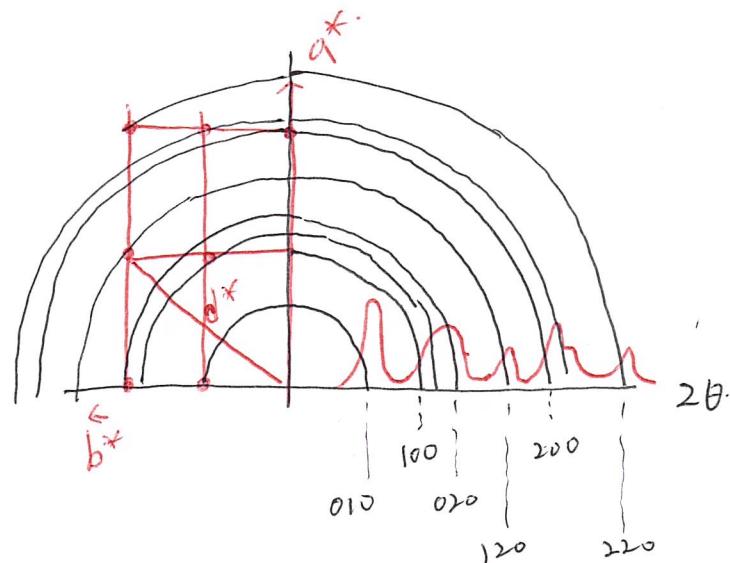


Summary

$(h, k, l) \rightarrow$ crystal system

position \rightarrow lattice parameter
 $(2\theta, d, g)$

Intensity \rightarrow type (bond, atomic, $n(\vec{g})$)



Classification of Methods.

Quantitative Analysis.

	Profile fitting	Whole-pattern decomposition	Rietveld refinement
Aim of analysis	Pattern decomposition	Pattern decomposition and refinement of unit cell parameters	Structure refinement
Range of analysis	Local peaks or peak clusters	whole pattern	whole pattern
Peak position	Independent parameters	Function of unit cell parameters.	— =
Integrated intensities (profile area)	"	— =	Function of structural parameters
Initial parameters required to start refinement	Nil	Approximate unit cell parameters.	Initial structural parameters (structural models)

Profile shape functions.

Gaussian

$$G = I_0 \exp \left\{ -\ln 2 \left(\frac{2\theta - 2\theta_0}{w} \right)^2 \right\}$$

Lorentzian

$$L = I_0 \left\{ 1 + \left(\frac{2\theta - 2\theta_0}{w} \right)^2 \right\}^{-n}, \quad n=1; 1.5; 2$$

Pseudo-Voigt

$$V = \eta L + (1-\eta) G \quad ; \quad (0 \leq \eta \leq 1)$$

Pearson VII

$$P = I_0 \left\{ 1 + \left(\frac{2\theta - 2\theta_0}{m\sigma} \right)^2 \right\}^{-m}$$

$2\theta_0$ = peak position.

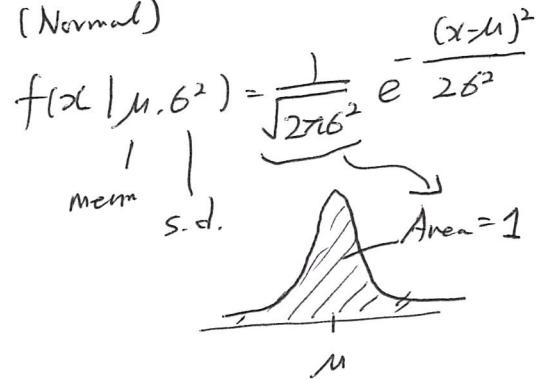
I_0 = peak intensity

w = FWHM / 2.

m = shape parameter.

Note: $(\text{FWHM})_k = T \tan^2 \theta_k + T \tan \theta_k + W$

Note: Gaussian distribution (Normal)



[Definition of R-indices.] = goodness of fit

$$R_F = \frac{\sum |(I_k(\text{obs}))^{1/2} - (I_k(\text{calc}))^{1/2}|}{\sum (I_k(\text{obs}))^{1/2}}$$

$$R_B = \frac{\sum |(I_k(\text{obs})) - (I_k(\text{calc}))|}{\sum I_k(\text{obs})}$$

$$R_p = \frac{\sum |y_i(\text{obs}) - (\frac{1}{c}) y_i(\text{calc})|}{\sum y_i(\text{obs})}$$

$$R_{wp} = \left[\frac{\sum w_i (y_i(\text{obs}) - (\frac{1}{c}) y_i(\text{calc}))^2}{\sum w_i (y_i(\text{obs}))^2} \right]^{1/2}$$